

Influence of the Annealing Temperature on the Optical and Solid State Properties of Lead Selenide (PbSe) Thin Films Grown by Chemical Bath Deposition (CBD) Technique.

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Abstract

The study of the influence of annealing temperature on Lead Selenide (PbSe) thin films deposited on glass substrates using chemical bath deposition technique were carried out. The growth of the first group of the films (Set 1: P₍₉₎ & P₍₁₄₎) was based on the decomposition of lead citrate and sodium selenosulphite in the presence of sodium citrate and sodium hydroxide with Ammonia and Triethylamine (TEA) acting as complexing agents and P.H stabilizers; while in the second group (Set 2: P₍₁₅₎), the reaction bath was made up of solutions of lead nitrate Pb(NO₃)₂, (PVA), distilled water (H₂O), ammonia (NH₃), sodium selenosulphite (Na₂SeSO₃) and Triethylamine [N(CH₂CH₂OH)], which was used as complexing agent. The deposited materials were identified by X-ray diffraction. In addition, optical and morphological investigations performed revealed the morphological structure of the film. The absorbance of the film for various region of the electromagnetic spectrum was observed. The optical absorbance was found to reduce with increase in wavelength. The optical band gap a ranges from 1.26 – 2.00eV with sample P₍₁₅₎ having the lowest direct band gap.

Keywords: *Annealing temperature*, Chemical Bath Technique, Lead selenide, thin films, Optical and Solid state properties, band gaps, transmittance, wavelength.

INTRODUCTION

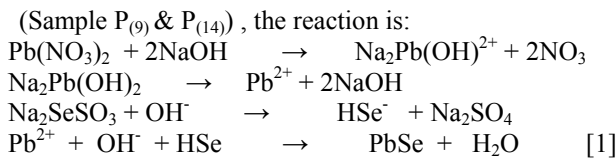
Metal chalcogenide thin films even their compounds have been of interest due their semiconducting nature and considerable application in the field of electronics and electro-optical devices. Based on this concept, intensive research has been performed in the past to study the fabrication and characterization of these thin films. Thus, the interest for Lead Selenide (PbSe) semi conducting thin films was motivated by its application in solar cell technology (1,2,3, 4). In the literature, a number of methods for the preparation of PbSe thin films were reported (7,8,9 10,11, 12). In laboratory, various methods of thin film deposition for production and characterization of semi conducting metal chalcogenides have been developed. Thus, the chemical deposition methodology for metal selenides such as mercury selenide (12,6), Silver selenide (13) lead selenide (11) and mercury sulphide are based on the decomposition of selenosulphite as source of selenide ions and thiosulphate as a source of sulfide ions precursors in an alkaline medium. The fabrication of metal oxides thin films of Fe₂O₃ (13), NiO (14) and CoO are based on thermal treatment of an aqueous solution that contains the metals (15) and urea as hydroxide ions precursors and subsequent thermal conversion of the obtained hydroxide thin films to oxides.

In this paper, we present the procedure for preparing lead selenide thin films using chemical bath deposition technique on glass substrates and look at their optical and solid state properties of the samples of deposited thin film using different constituents. The structure and nature of the band gap of the films would be discussed followed by the X-ray diffraction analysis and photo micrographic data.

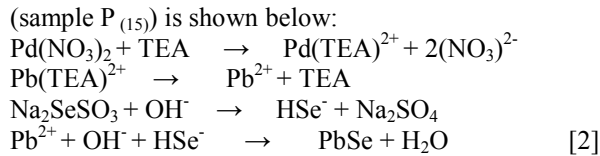
EXPERIMENTAL DETAILS

PbSe thin films were deposited on 76mm x 26mm x 1mm clean glass slide by chemical bath deposition (CBD) technique, (16). The 'set1' of the films (P₍₉₎ & P₍₁₄₎) contained 5ml of 1M Pb(NO₃)₂ dissolved in 5ml of 1M Na₂SeSO₃, followed by the addition of 4ml of 1M sodium citrate [C₃H₄(OH)COONa]₃.2H₂O and 3ml of 2M NaOH as a complexing agent. The mixture was made up to the required volume with addition of 35ml of PVA (Polyvinyl Alcohol). The resulting solution was stirred for a few seconds with a glass rod stirrer. A glass slide was inserted in the reaction bath and held vertically in a synthetic foam cover. This process was repeated for different dip time in hours of: P₉ (1¹/₄ hrs) and P₁₄ (1¹/₂hrs) at a deposition temperature of 75⁰C in an oven. 'Set 2' (sample P₍₁₅₎) was deposited the same way but the deposition bath contained: solution of lead nitrate Pb(NO₃)₂, PVA, Distilled water (H₂O), Ammonia (NH₃), Sodium Selenosulphite (Na₂SeSO₃) and TEA [N(CH₂H₂OH)₃] used as complexing agent. At the end of the deposition times, the slides were taken out, rinsed with distilled water and allowed to dry in electronic oven. The slides were observed to have been coated with dark deposits. The equations of the reactions are shown below.

For set 1:



The reaction for set 2:



They were later annealed at different temperature for one hour each as shown in the table 1. The band gaps of the films were determined by using the absorbance and transmittance measurements from Unico-UV-2102 PC spectrophotometer at normal incident of light in the wavelength range of 200-1000nm. The optical band gaps of the films would be obtained by using Tauc's Plot of $(\alpha \text{ hv})^2$ Vs (hv) (17). The value of α was determined from transmittance spectra using:

$$T = I / I_0 = \exp(-\alpha x) \quad [3]$$

Where: I_0 and I , are the incident flux and transmitted flux passing through a specimen of thickness (Xmm) with absorption coefficient (α) and transmittance (T) (18). However the fundamental absorption which corresponds to the electron excitation from the valence band to the conduction band can also be used to determine the nature and value of the optical band gap using:

$$(a \text{ hn})^{1/n} = \text{constant} - E_g \quad [4]$$

Where A = constant, E_g = band gap of the material and the exponent 'n' depends on the type of transition of which the values for direct allowed, indirect allowed and direct forbidden transition are $n = \frac{1}{2}$ and $3/2$ respectively. The photon energy at the point where $(\alpha \text{ hv})^2$ is zero represents the band gap E_g , which is determined by extrapolation.

RESULTS AND DISCUSSION

Figure 1 shows the plot of absorbance, transmittance and reflectance verses wavelength of PbSe thin films (sample P₍₉₎&P₍₁₄₎) deposited in this work while fig2 contains the graphs for sample P₍₁₅₎. For sample P₍₉₎ & P₍₁₄₎, the absorbance generally decreased with wavelength and has relatively low values in the IR region of the solar spectrum. A strong absorption was observed at wavelength range of 280-400nm, hence the film has potential application in fabrication of solar cell. The absorbance decreased as band gap decreased.

The transmittance spectra displayed in fig 1b shows downward trend in the transmittance of the films as band gap increases. The films show increase in transmittance as the wavelength increases and has over (80%) transmittance at NIR region of the spectrum of approximately 1000nm.

Fig 1c is a plot of reflectance as a function of wavelength for PbSe thin films of sample P₍₉₎ & P₍₁₄₎. The film shows an average reflectance of 20.5% in the wavelength rage of 300-640nm.

Fig 1d shows the refractive index of the films. Sample P₉ and P₁₄ showed a sharp increase in value of 'n' from 1.5-2.3 between 1.2-1.75eV and a gentle increase of 0.2 between 1.75-4.25eV, hence it has an average refractive index 'n' of 2.3.

Table 1: Band gap, Deposition temperature, Annealing temperature & Time of Deposition

S/NO	PdSe films	Band gap hv (ev)	Deposition temperature (°C)	Annealing temperature (°C)	Dip Time (hrs)
1.	P ₍₉₎	1.50	75	100	1 ^{1/4}
2.	P ₍₁₄₎	2.00	75	300	1 ^{1/2}
3.	P ₍₁₅₎	1.26	75	300	1 ^{1/2}

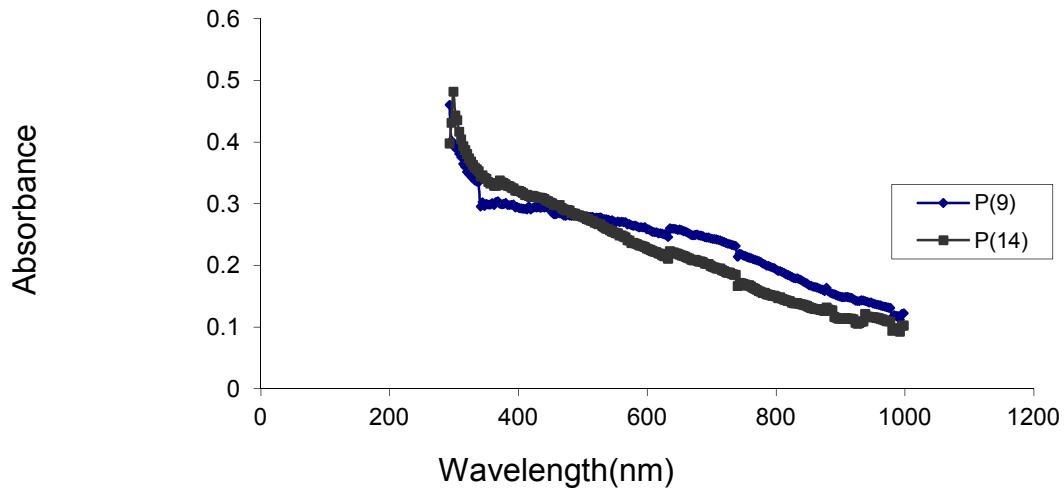


Fig 1a: Absorbance Vs Wavelength for PbSe

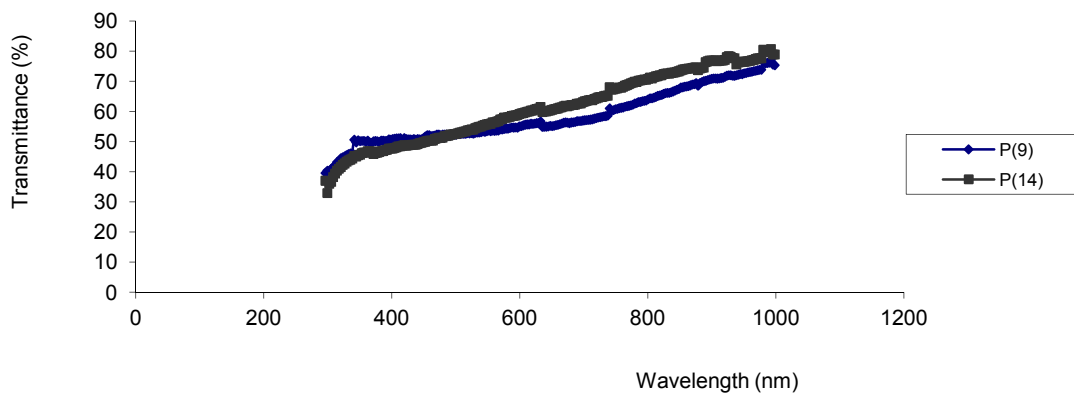


Fig:1b Transmittance vs. wavelength for PdSe

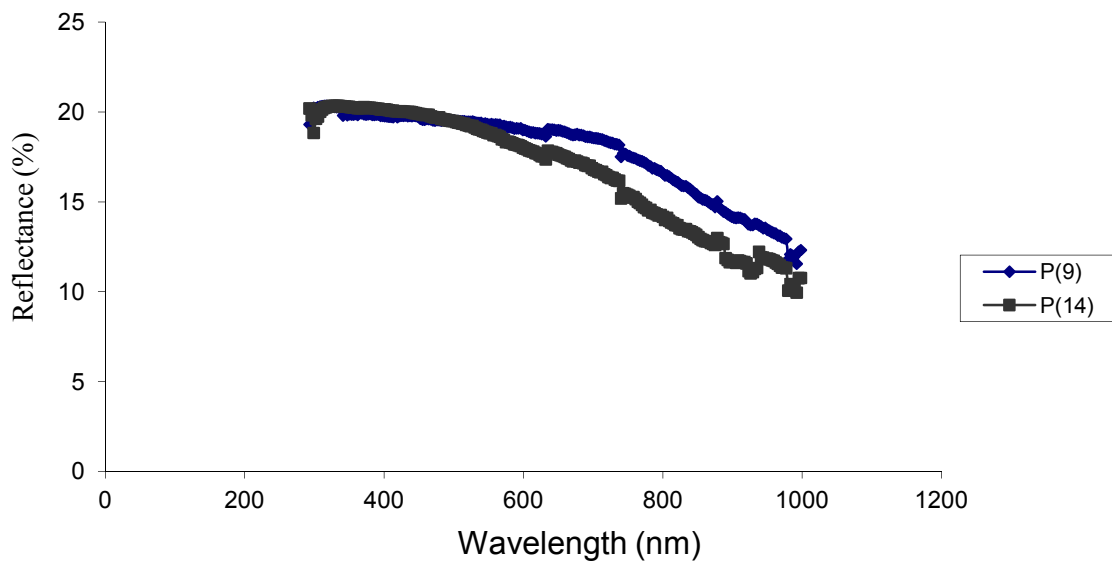


Fig 1c: Reflectance vs. wavelength for PdSe

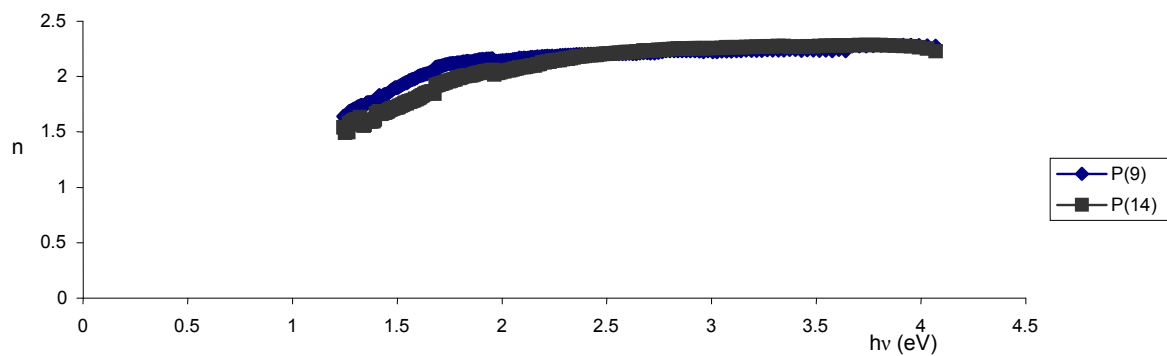


Fig 1d: Refractive index vs. Photon energy for PdSe

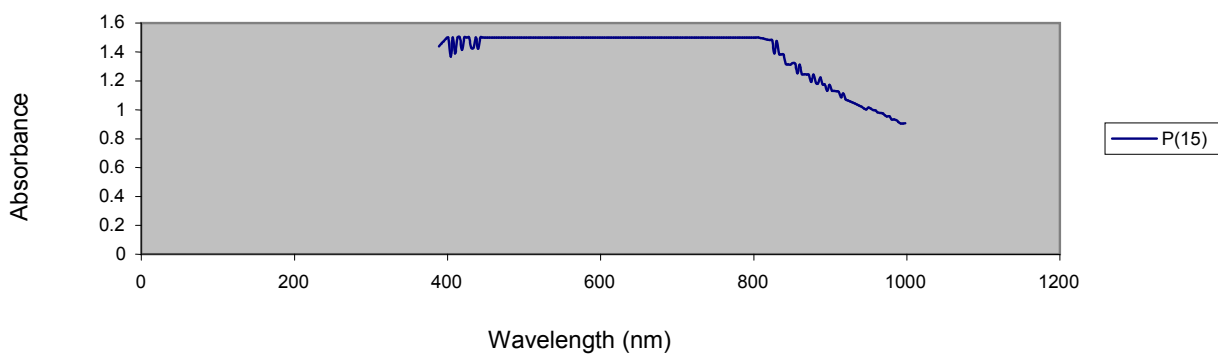


Fig 2a: Absorbance vs. wavelength P(15) PdSe

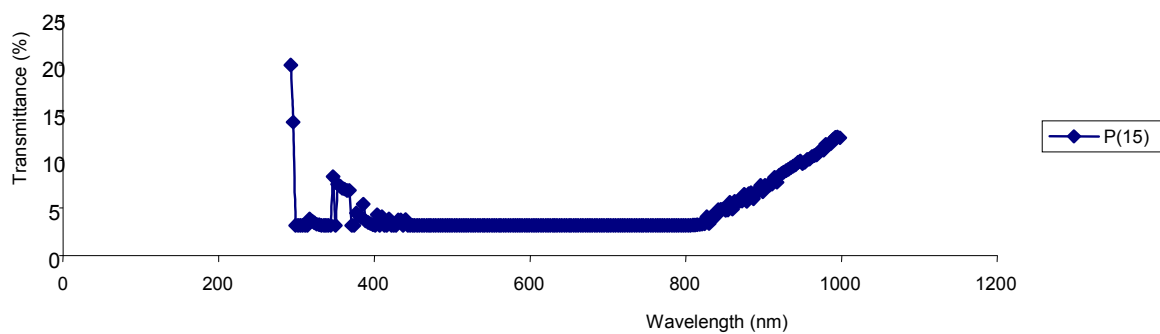


Fig 2b: Transmittance vs. wavelength P(15) PdSe

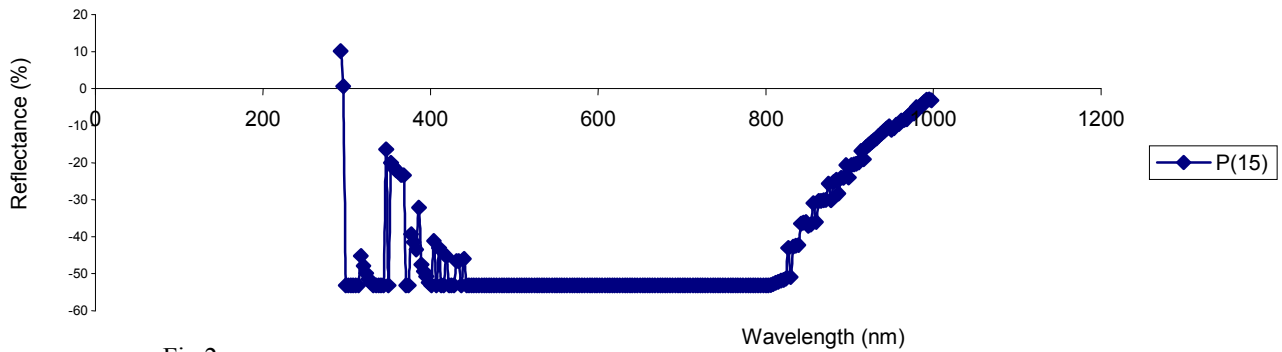


Fig 2c:

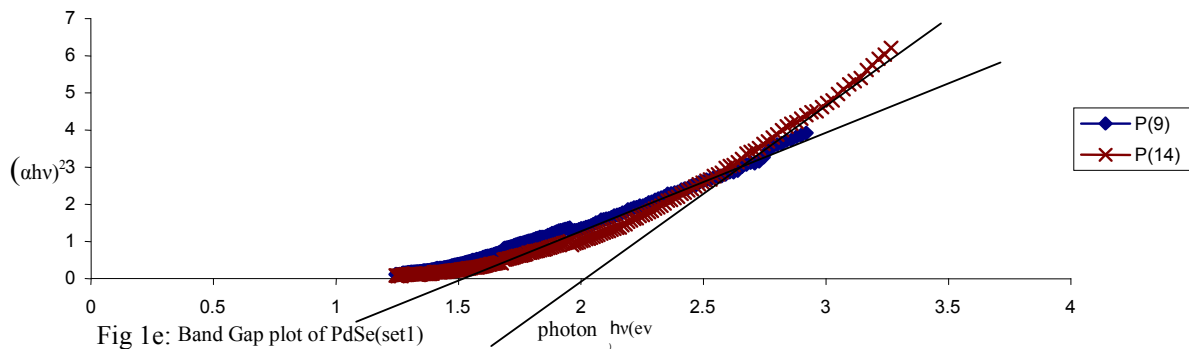


Fig 1e: Band Gap plot of PdSe(set1)

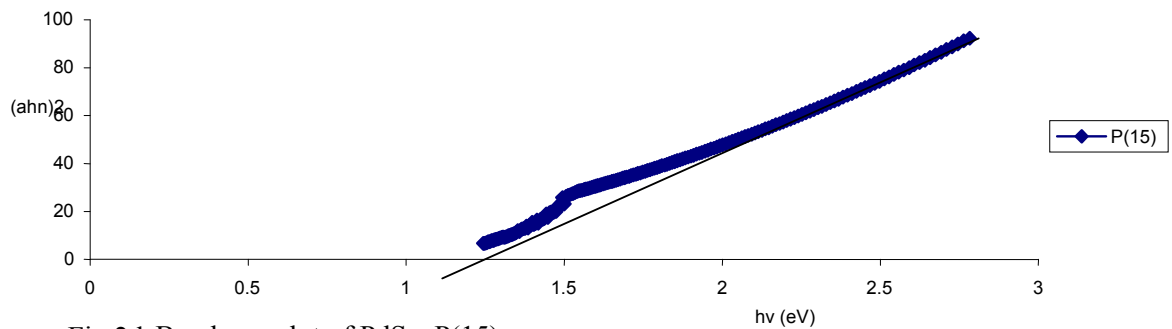


Fig 2d: Band gap plot of PdSe, P(15)

Fig2a presents a striking observation of sample $P_{(15)}$ whose constituent is completely different from the other two. The absorbance spectrum shows that it has very high and uniform absorbance of 1.5 throughout VIS and NIR regions of solar radiation. However, it has an extra ordinarily non reflectance property of -53% in the range of 300-840nm. It also has a very low transmittance of less than 5% in the same range of spectrum mentioned before. The characteristic shows that it has one of the most important properties of a thin film suitable for producing solar cell. In this respect, it is suitable for upper surface absorber of solar cell.

The values of the band gaps obtained for PbSe lie in the range of 1.26 – 2.00eV. It was observed that the band gap increased with increase in the annealing temperature which is quite different from the existing trend in literature reported elsewhere (Enriquez, 2003; Erat et al, 2007). With this range of band gap, it was observed that the band gap is generally good for opto-electronic applications.

X – Ray diffraction analysis was carried out on the chemical bath deposited PbSe thin films. The samples were grounded to below 100 meshes in an agate mortar and then loaded into a 2.5mm diameter circular cavity

holder and ran on an MD 10 mini diffractometer. CuK_α was selected by a diffracted beam monochromator. The thin films were scanned continuously between 0 to 75 at a step size of 0.03 and at a time per step of 0.15sec. Phase identification was then made from an analysis of intensity of peak versus 2θ .

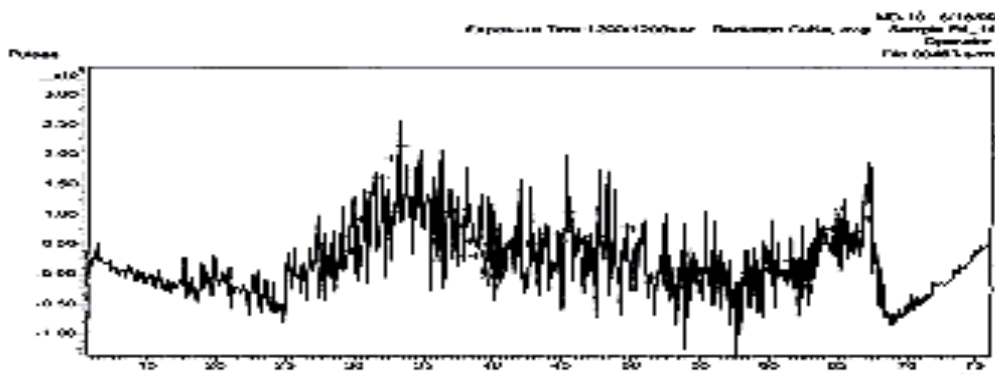


Fig.3a:XRD pattern for PbSe

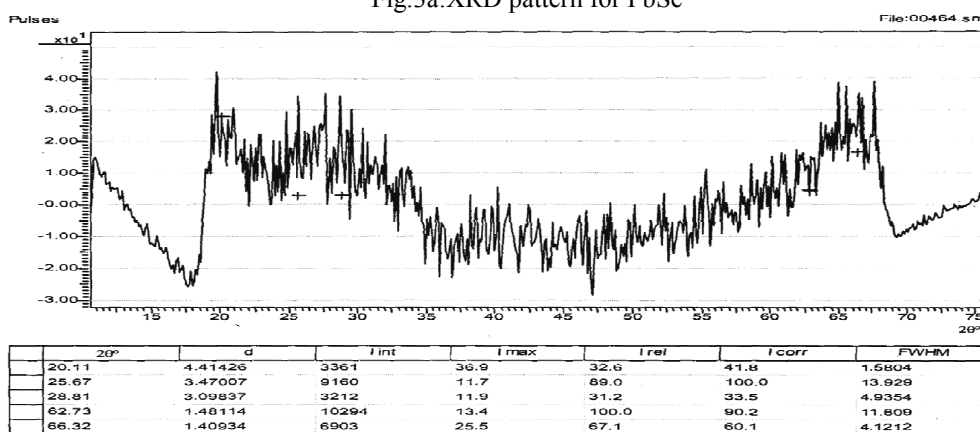


Fig 3b:XRD pattern for PbSe

Fig 3a displayed an XRD crystal pattern with maximum peak value of 4.25 at 2θ value of 20.0° and 39.0 at the range of 64.5° – 68.6° of 2θ . The XRD pattern displayed in fig.3b shows several peaks at 2θ values of around 20.11° , 25.67° , 28.81° , 62.73° and 66.32° . The 2θ values of 20.11 ($d = 4.41426 \text{ \AA}$) and 62.73° [$d = 1.48114 \text{ \AA}$] corresponding to the diffraction lines produced by (32.9) and (100.0) planes respectively. The existence of identifiable peaks in the diffractograms suggests that the films are not amorphous but crystalline in nature (mane, et al, 1999). However the presence of several peaks suggests vibrations from impurities in the annealing oven or glass substrate used. A comparison of the observed peaks with standard JCPDS cards show that the samples possess a cubic crystal (orthorhombic in nature) of blue-gray metallic colour obtained at 19 reflections in pattern at room temperature of 25°C . The calculated grain size of the thin film is about $1.91 \times 10^{-10} \text{ m}$ which is approx. $2.0 \text{ \AA} = 0.2 \text{ nm}$.

CONCLUSION

The deposition of PbSe thin films have been successfully carried out in alkaline medium using chemical bath deposition technique. The spectral characteristics of the two sets of films showed that the effect of chemical constituents –in this case the complexing agent on the optical and solid state properties of PbSe was so conspicuous that the two sets of graphs are not related, consequently their characteristic nature. Hence the behaviour of any grown thin film depends to a large extent on the constituent of the solution from where it was deposited disregarding the environmental impurities. The deduction from the spectrophotometers showed that the band gap ranged between 1.26eV and 2.00eV and the grain size ranged from 11×10^{-10} to $93 \times 10^{-10} \text{ m}$. Some of the films were found to have high absorbance in the range of 280–400nm and depreciates as the wavelength

increased. They had generally low transmittance and an average reflectance of 20.5% in the range of 300-640nm. The film hence has the potential for use in the solar cell fabrication, window screen and antireflection coatings while the characteristic zero reflectance of sample P₍₁₅₎ shows its potential for solar cell and solar warmer fabrication.

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